



**Dipartimento
Meccanica
Matematica
Management**

MUR
Dipartimento
di Eccellenza
2018-2022
2023-2027

"Data Science Applications in Physics" Winter School in Tirana 2025

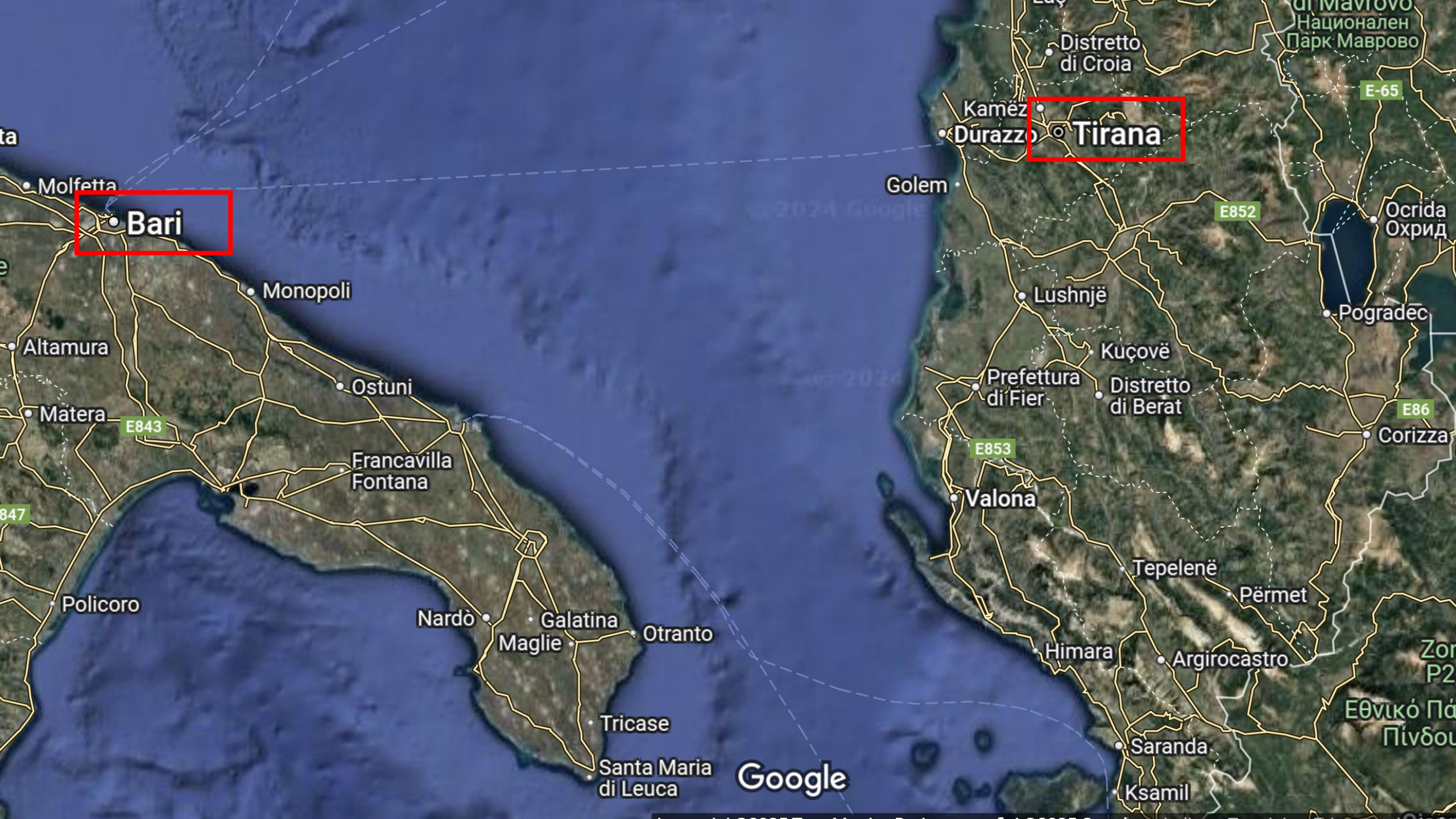


Optical and Interferometric Methods for Material Characterization and Dimensional Analysis

Mon 27th January 2025

Giovanni Pappalettera

Faculty of Natural Sciences
Hall 413 B - Tirana



Bari

Tirana

Google



Politecnico
di Bari



ENNIO CUSANO



POLITECNICO DI BARI IN NUMBERS

9.755

ENROLLED STUDENT WITH
2.980 WOMEN AND 132
FOREIGN STUDENTS

05

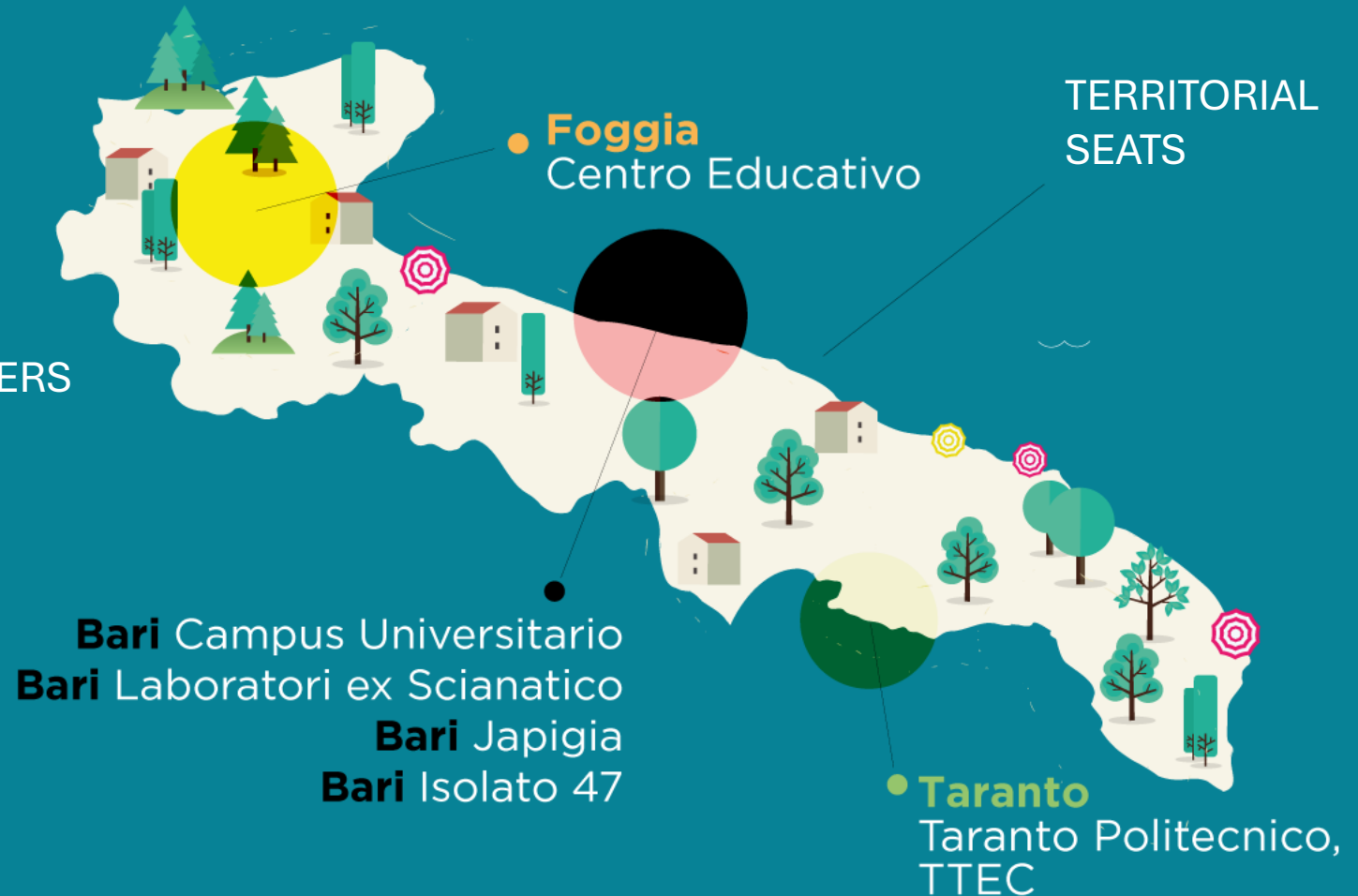
DEPARTMENTS

655

PROFESSORS and RESEARCHERS
184 WOMEN

265

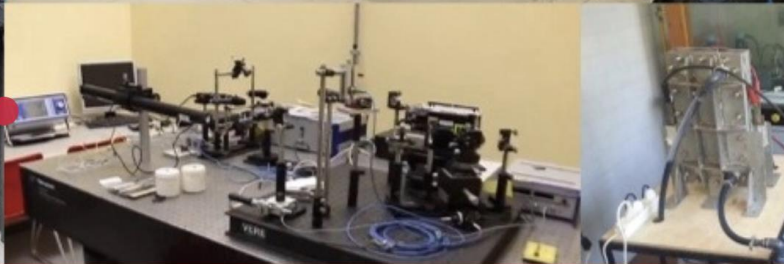
NON TEACHING STAFF
126 WOMEN





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Meccanica
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2018-2022
2023-2027



SEAL of *EXCELLENCE DEPARTMENT*

2018-2022

2023-2027

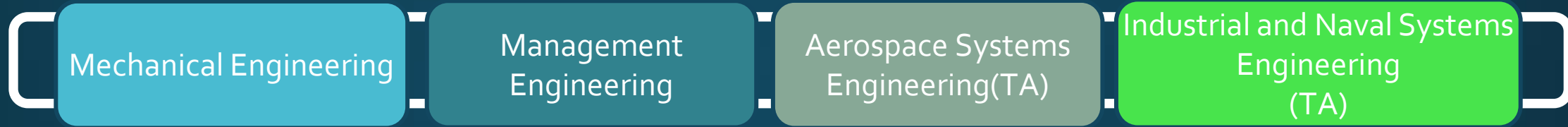
A recognition given by the Italian
Ministry of University and Research
Selecting among 800 University
Department

Best Ranking in the Industrial Area

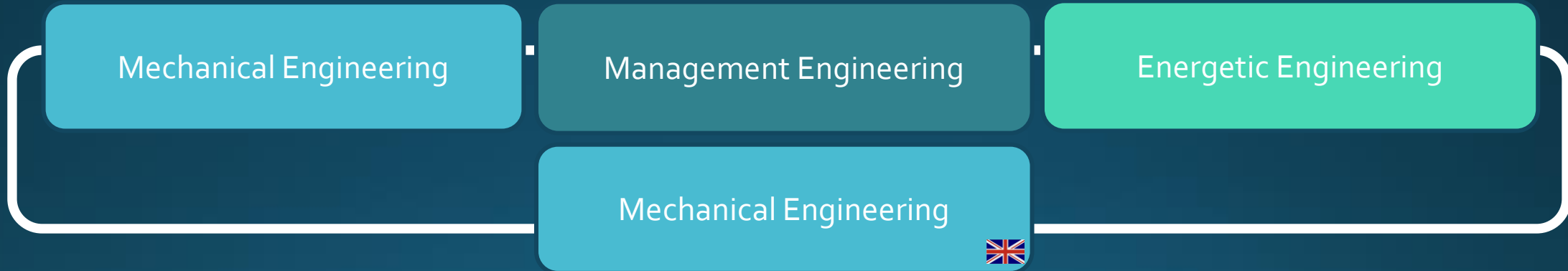
MECHANICS, MATHEMATICS and MANAGEMENT DEPARTMENT



Bachelor

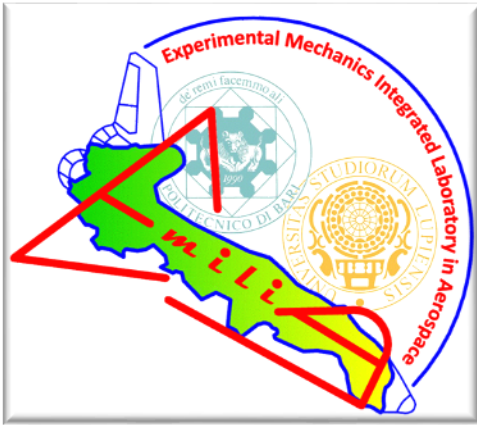


Master



Post Lauream





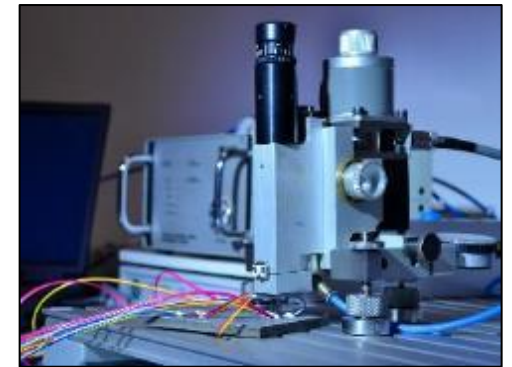
EXPERIMENTAL MECHANICS Lab.

Coordinator: Katia Casavola, ME, PhD, Full Professor – katia.casavola@poliba.it

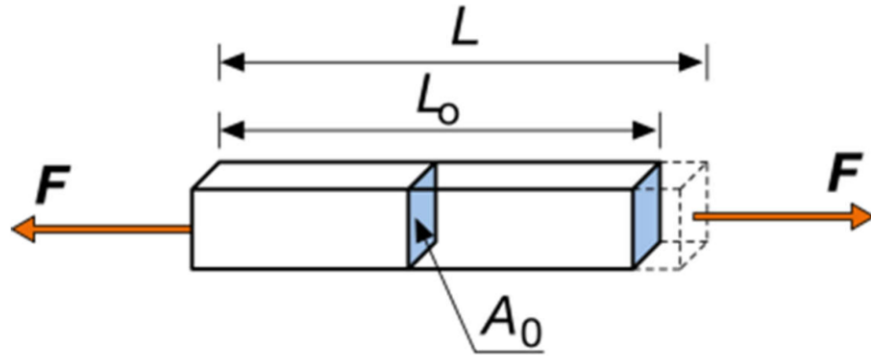
Staff: C. Barile, V. Moramarco, G. Pappalettera - Phd, Ass. Prof. / Researchers

Others: 1 researcher RTDA, 3 post doc, 3 PhD students, 1 technician

Founder of the Lab: Carmine Pappalettera – Prof. Emeritus



Stress and Strain

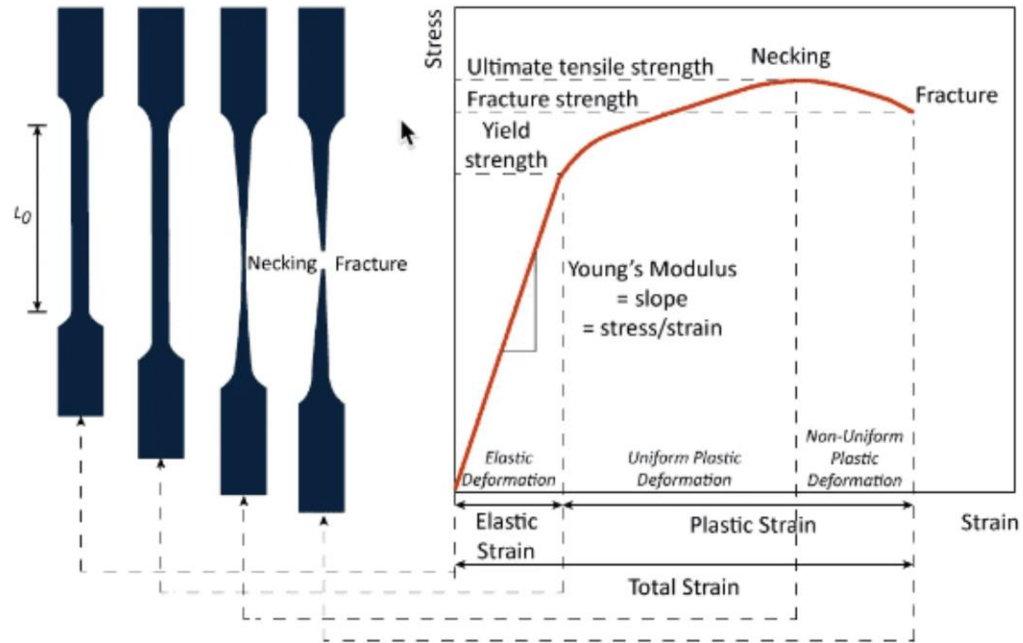


$$\sigma = \frac{F}{A}$$

Stress

$$\varepsilon = \frac{\Delta L}{L_0}$$

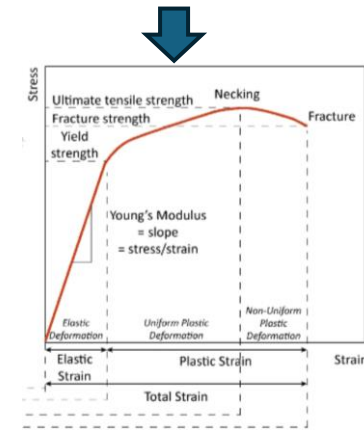
Strain



Apply Load



Measure Deformation



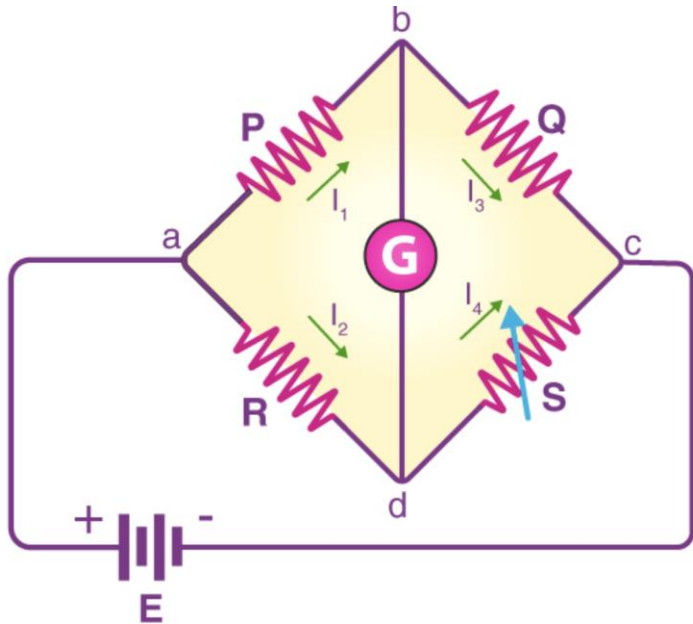
Get Stress/Strain Curve

Strain Measurement: Strain Gauge

Dimensional variation of the strain gauge change its resistivity

$$R = \frac{\rho l}{A}$$

Resistivity (Ω/m)
Length of wire
Resistance (Ω)
Cross sectional area of wire (mm^2)

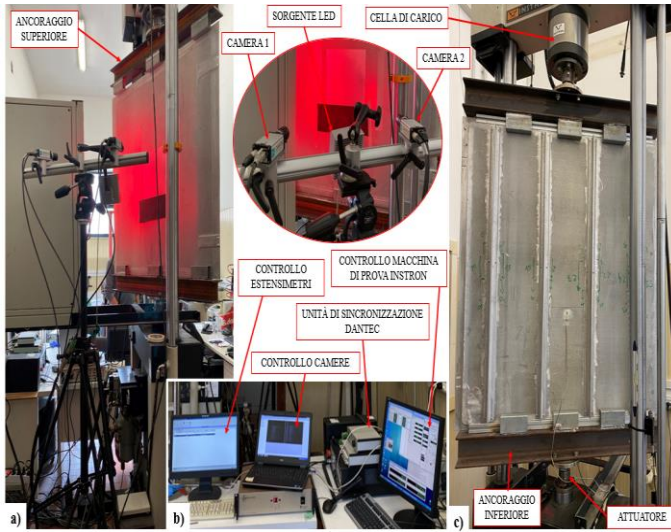


Wheatstone Bridge

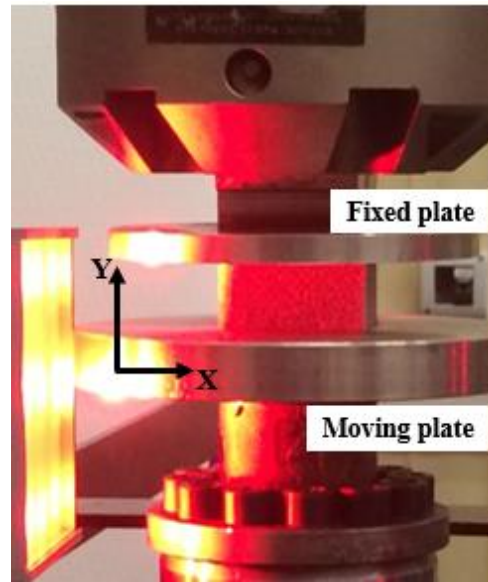


$$\epsilon = \frac{l - l_0}{l_0}$$

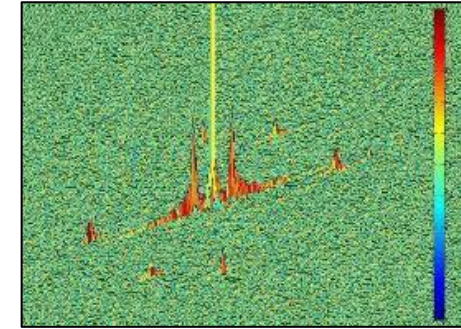
Strain Gauges limitations



Aluminum foam stringered panel



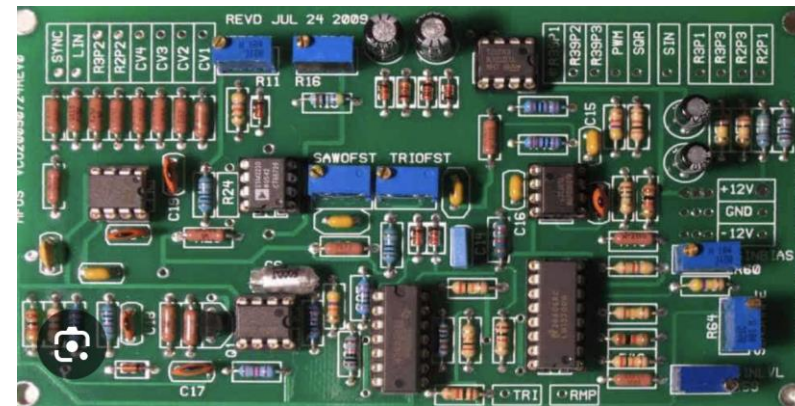
PU foam



Corrosion onset



CFRP Composite



PCB Board

Why optical Methods?

Every time we are looking for:

- No contact
- No destructive
- High resolution
- High sensitivity

Which optical Methods?

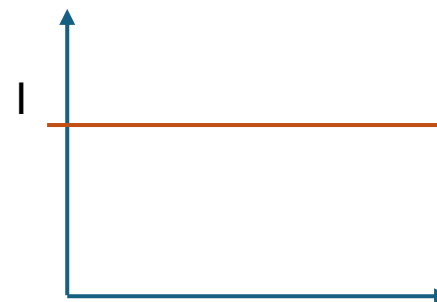
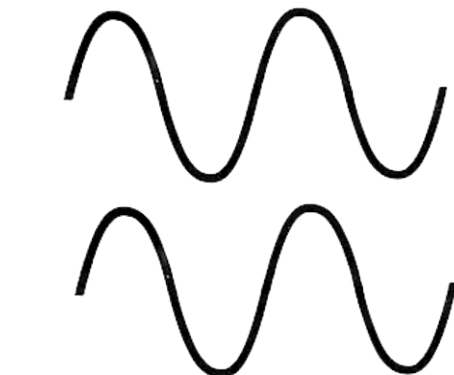
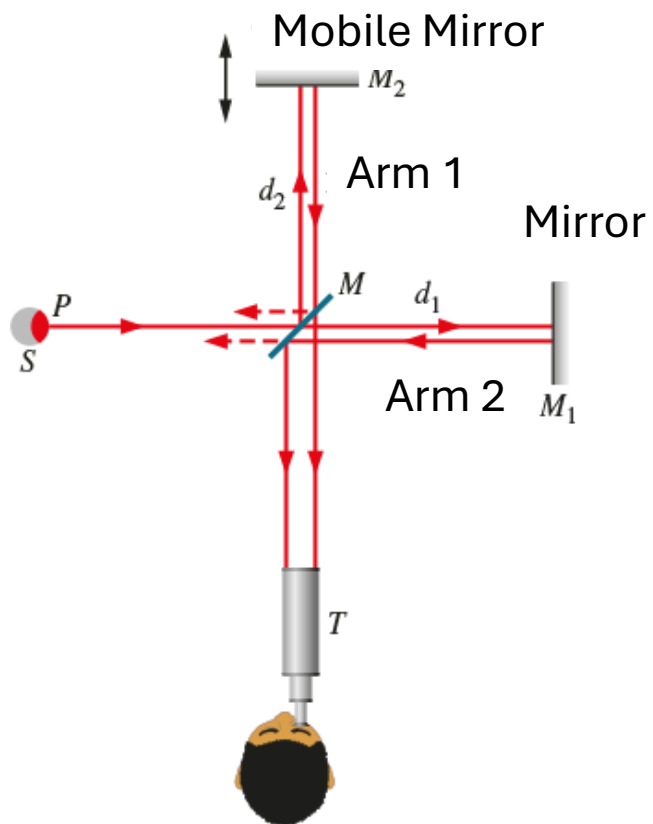
- **Speckle Interferometry**
- **Moirè Methods**
- **Fringe Projection Methods**
- Digital Holography
- Shearography
- Photoelasticity
- **DIC**
-



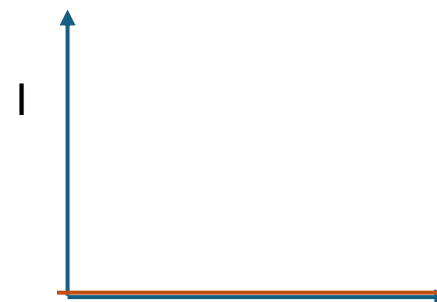
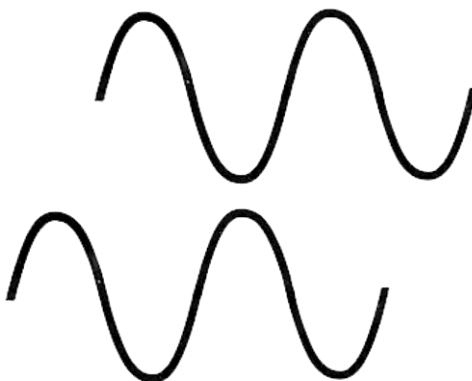
Interferometric Implementation

Non Interferometric Implementation

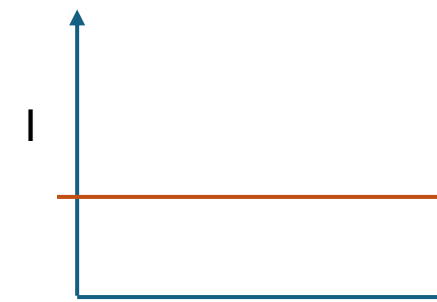
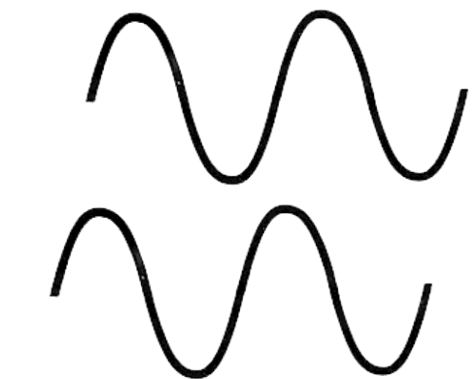
Interferometric Methods



Constructive



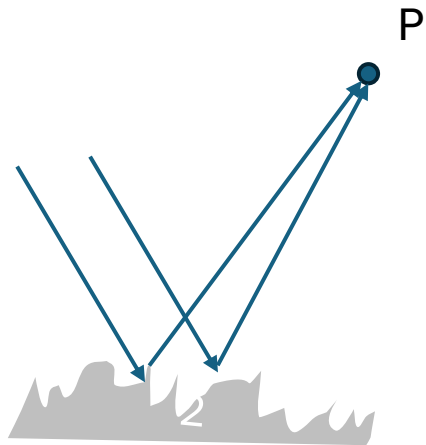
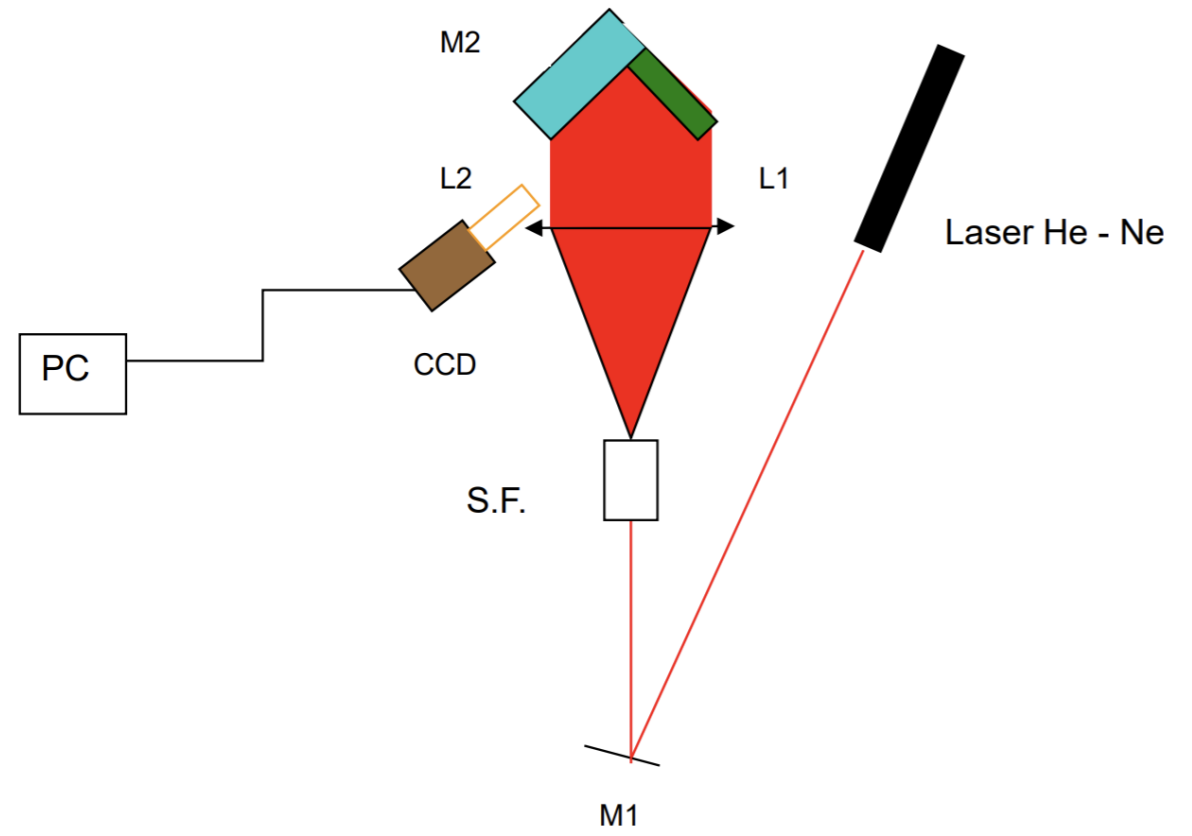
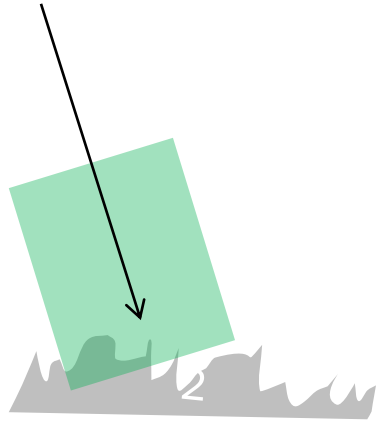
Destructive



Intermediate

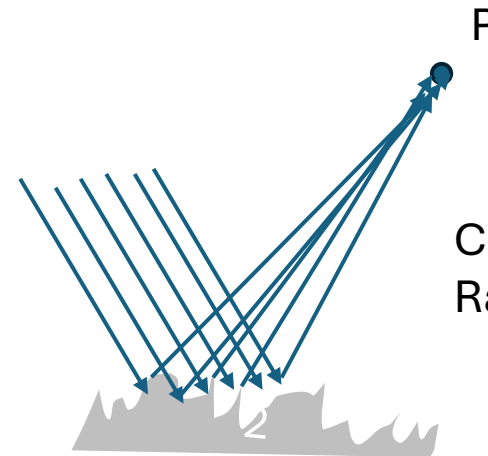


Speckle Methods



? Intensity?

Constructive/Destructive



? Intensity?

Constructive/Destructive
Randomly determined

Principle of Fringe Analysis

$$h \longleftrightarrow \Phi$$

Basic idea is the relationship between phase in the pattern and the quantity to be measured

Fringes Generated by Laser Interference

$w(x, y, t) = a(x, y)e^{i[\Phi(x, y)]}$, This express the light wavefront at a given instant t

$\Phi(x, y) = \frac{2\pi h(x, y)}{\lambda}$ Phase can be express as a function of the travelled path h(x,y)

Principle of Fringe Analysis

Fringes Generated by Laser Interference

Let's suppose now to have two wavefront and let's call them reference and test

$$w_r(x, y) = a_r(x, y)e^{i[\Phi_r(x, y)]},$$

$$w_t(x, y) = a_t(x, y)e^{i[\Phi_t(x, y)]},$$

Let's make them interfere on a surface

$$w(x, y) = w_r(x, y) + w_t(x, y).$$

Leading to an intensity

$$I(x, y, t) = |w_r(x, y) + w_t(x, y)|^2,$$

Principle of Fringe Analysis

$$I(x, y, t) = I'(x, y) + I''(x, y) \cos [\Phi_t(x, y) - \Phi_r(x, y)],$$

Where

$$I'(x, y) = a_r^2(x, y) + a_t^2(x, y)$$

$$I''(x, y) = 2a_r(x, y)a_t(x, y)$$

$$\cos\alpha \cdot \cos\beta = \frac{1}{2} [\cos(\alpha + \beta) + \cos(\alpha - \beta)]$$

We can set

$$\phi(x, y) = \Phi_t(x, y) - \Phi_r(x, y),$$

$$\sin\alpha \cdot \cos\beta = \frac{1}{2} [\sin(\alpha + \beta) + \sin(\alpha - \beta)]$$

We get the fundamental equation of the fringe analysis

$$I(x, y) = I'(x, y) + I''(x, y) \cos [\phi(x, y)],$$

Principle of Fringe Analysis

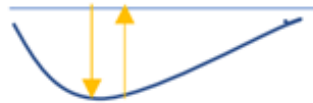
$$I(x, y) = I'(x, y) + I''(x, y) \cos[\phi(x, y)],$$

Background

Contrast

Phase

$$h(x, y) = \frac{\phi(x, y)\lambda}{2\pi},$$



$$h(x, y) = \frac{\phi(x, y)\lambda}{4\pi}.$$

Principle of Fringe Analysis

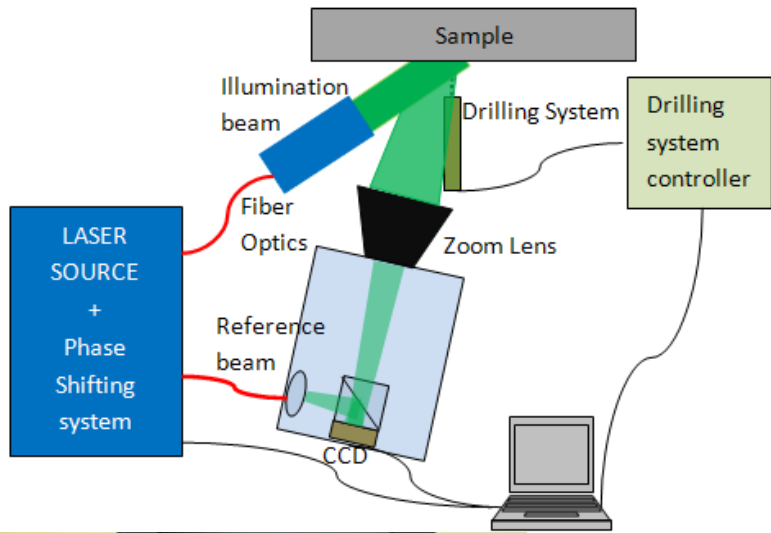
How I can extract the phase? **PHASE SHIFTING**

$$\left\{ \begin{array}{l} I_1(x, y) = I'(x, y) + I''(x, y) \cos[\phi(x, y) - \alpha], \\ I_2(x, y) = I'(x, y) + I''(x, y) \cos[\phi(x, y)], \\ I_3(x, y) = I'(x, y) + I''(x, y) \cos[\phi(x, y) + \alpha]. \end{array} \right.$$

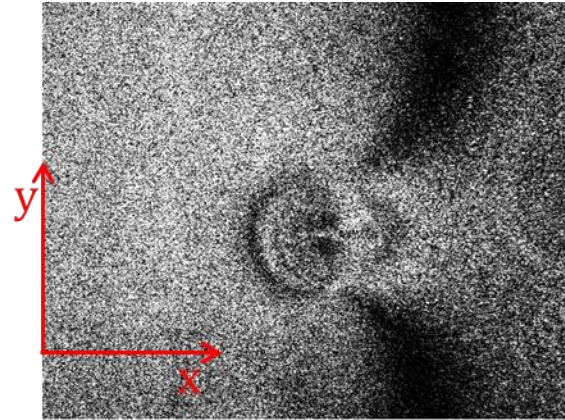
Three Step Phase Shifting

$$\phi(x, y) = \tan^{-1} \left[\frac{(1 - \cos \alpha)(I_1 - I_3)}{\sin \alpha(2I_2 - I_1 - I_3)} \right]$$

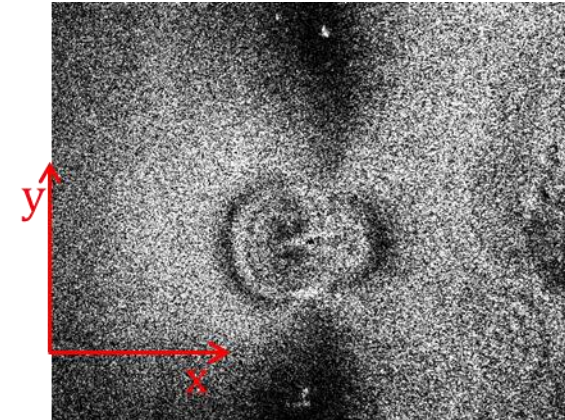
Principle of Fringe Analysis: one application



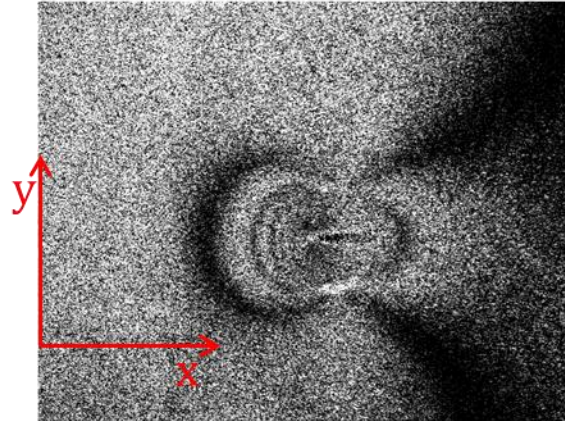
0,1mm



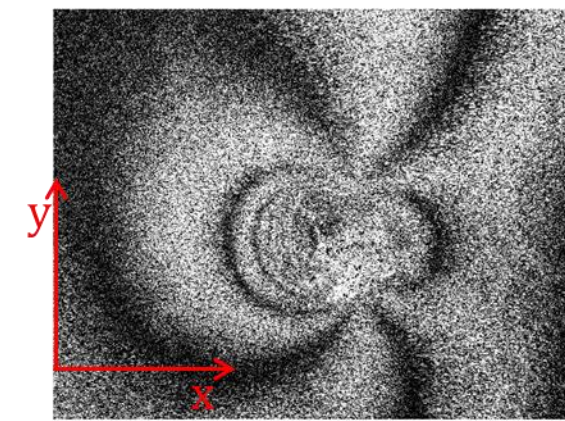
0,2mm



0,3mm



0,4mm

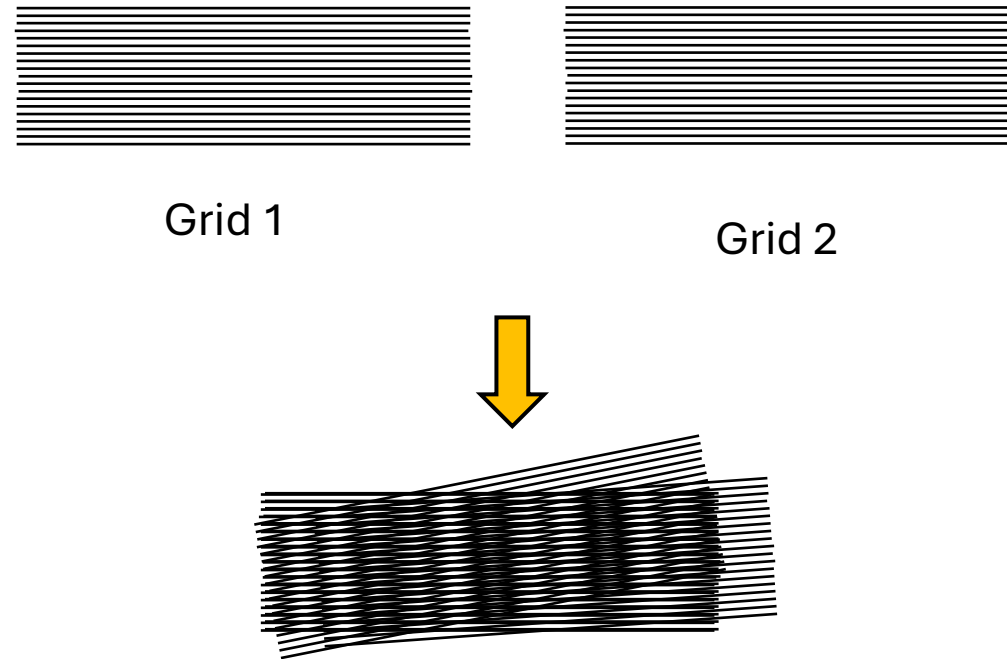


- 1 DPSS, $\lambda=532$ nm, P=25 mW laser source
- 1 CCD camera 640x480 ;
- 1 Electronically controlled cutter
- 1 Precision Translational stage
- 1 Compressed air cleaning system
- 1 PC

Speckle is a noise on the fringe pattern

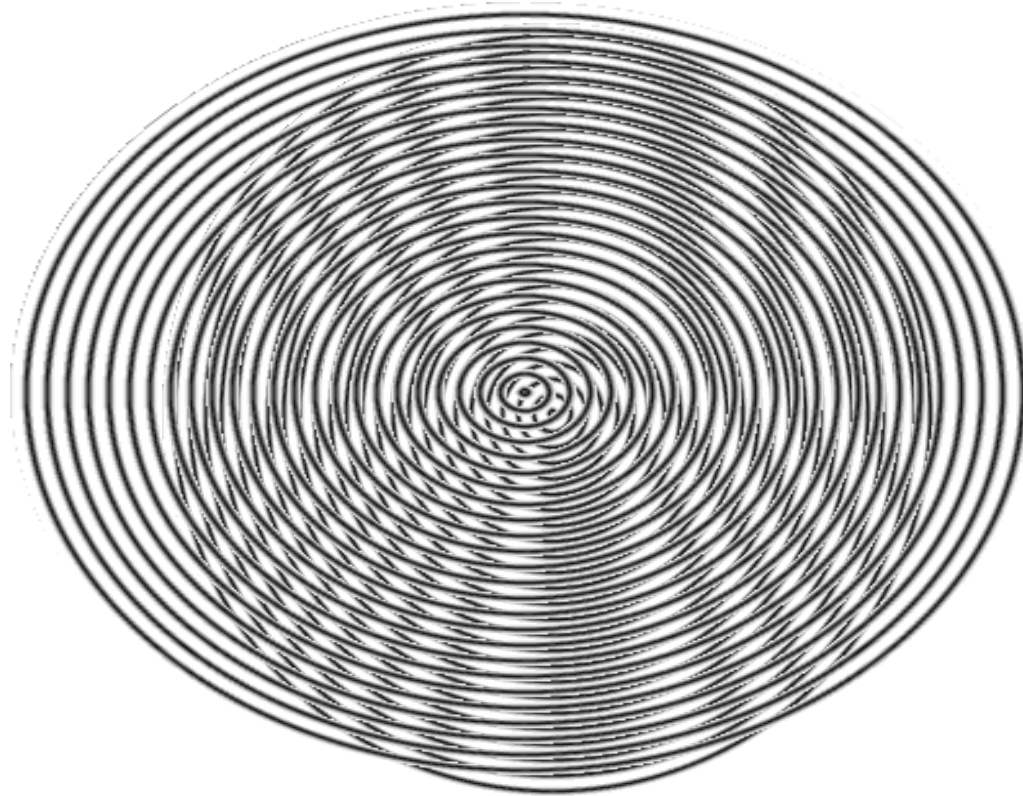


Moiré Principle

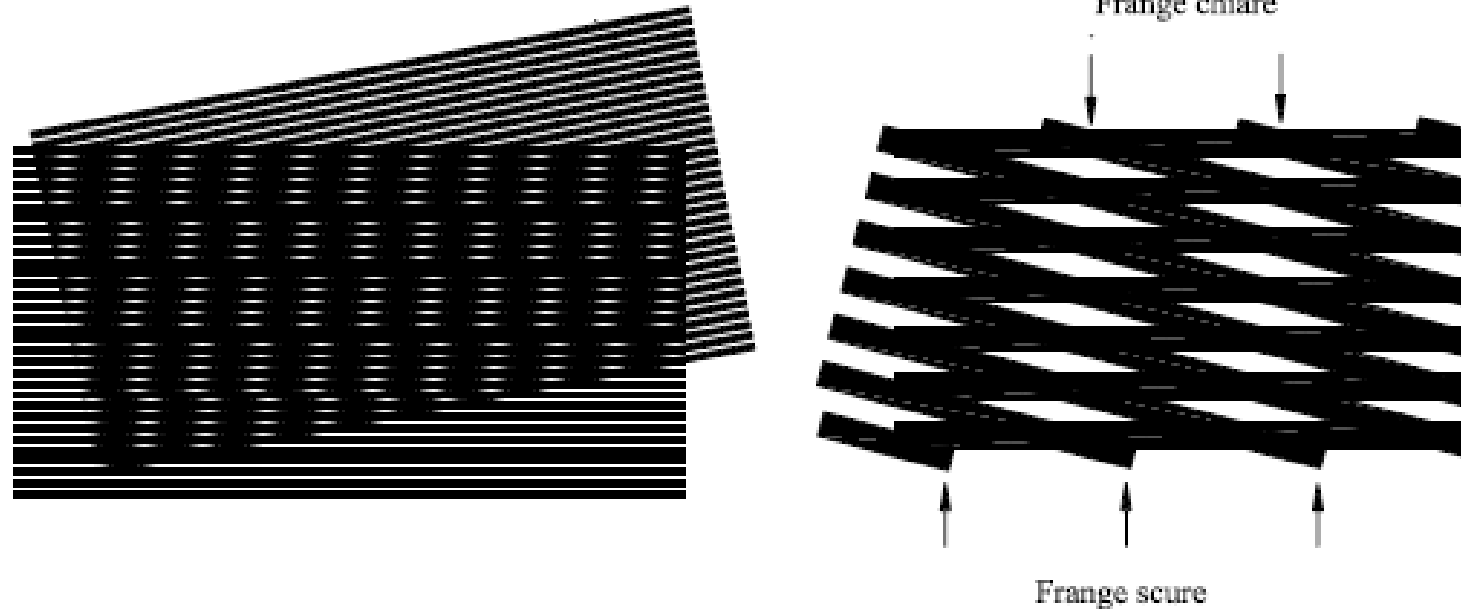


All the methods allowing to exploit this effect, overlapping even electronically these two grids are called moiré

Moiré Principle



Moiré Method



- Geometric Moiré
- Interferometric Moiré
- Reflection Moiré
- Shadow moiré



$$u=pNx$$

$$v=pNy$$



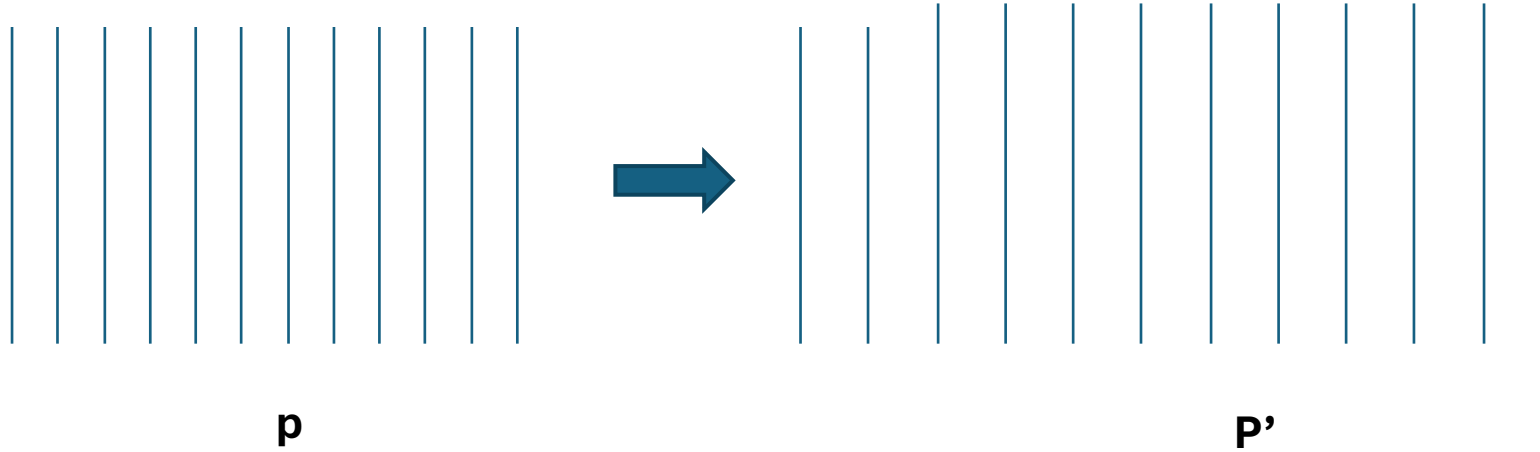
In plane displacement

$$w=KpNz$$



Out of plane displacement

Moiré Method



$$p' = (dp) / (d \pm p)$$

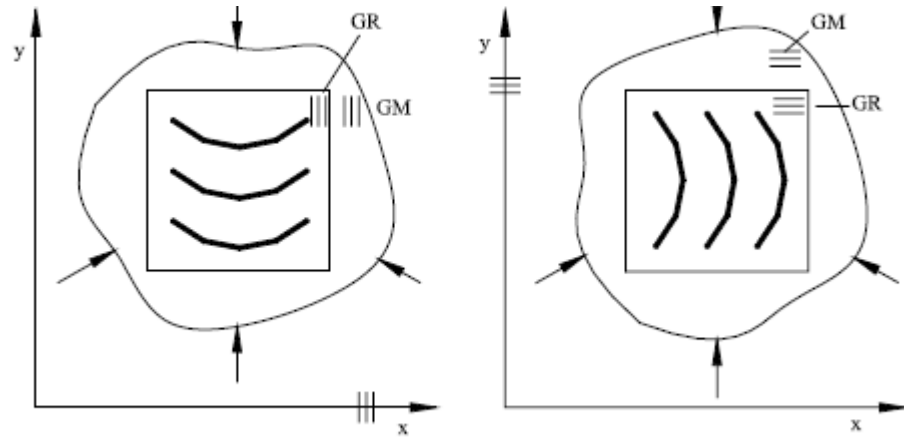
d = moiré fringes distance

$$\varepsilon_x = \frac{\partial u}{\partial x}, \quad \varepsilon_y = \frac{\partial v}{\partial x}, \quad \gamma_{xy} = \frac{\partial u}{\partial y} + \frac{\partial v}{\partial x}$$



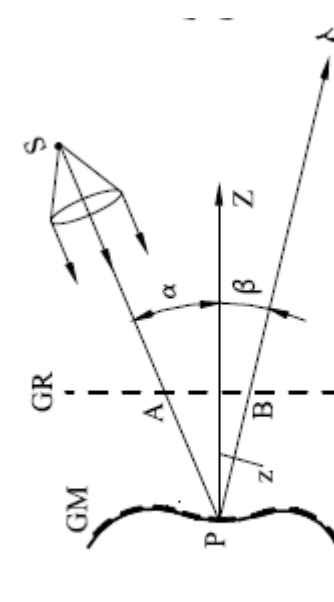
$$\varepsilon_x = p \frac{\partial N_x}{\partial x}, \quad \varepsilon_y = p \frac{\partial N_y}{\partial y}, \quad \gamma_{xy} = p \left(\frac{\partial N_x}{\partial y} + \frac{\partial N_y}{\partial x} \right)$$

Moiré Method



$$\varepsilon_x = p \frac{\partial N_x}{\partial x}, \quad \varepsilon_y = p \frac{\partial N_y}{\partial y}, \quad \gamma_{xy} = p \left(\frac{\partial N_x}{\partial y} + \frac{\partial N_y}{\partial x} \right)$$

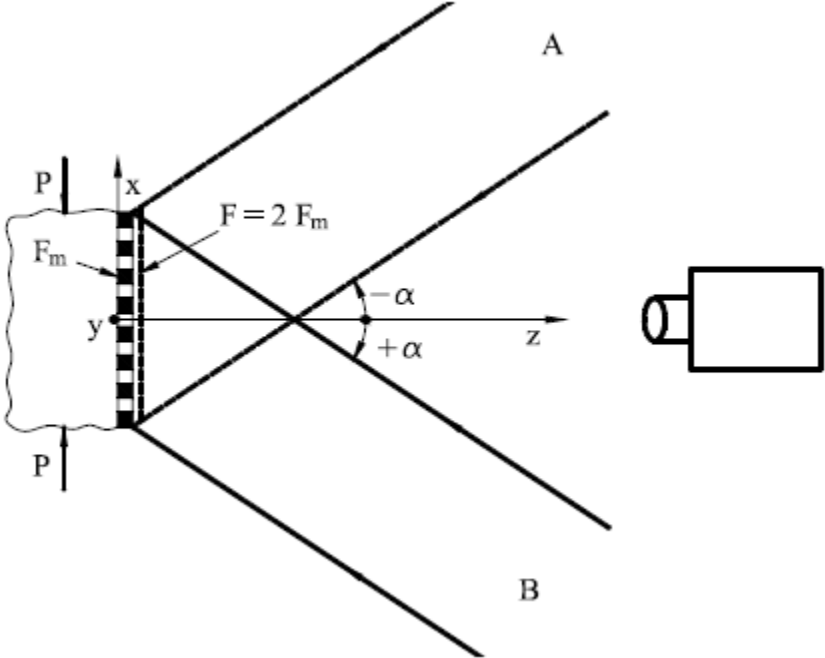
Plane moiré



$$z = \frac{p}{\tan \alpha + \tan \beta} N$$

Shadow Moiré

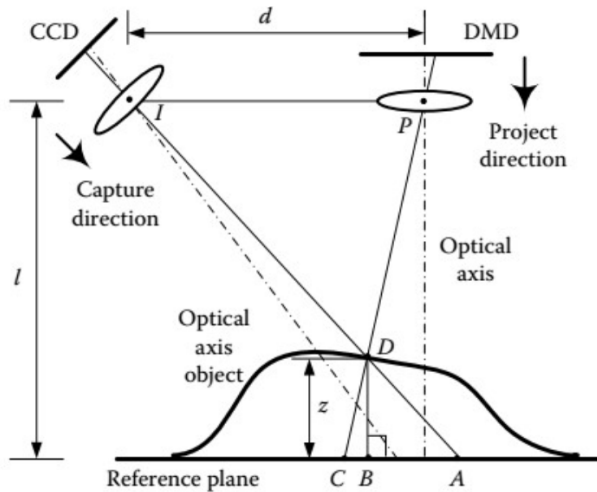
Moiré Method



$$u = pNx$$

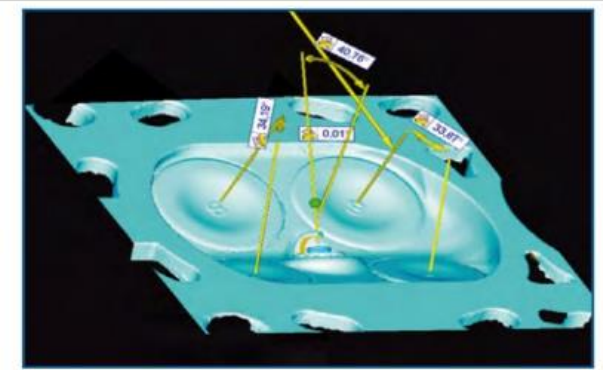
Interferometric Moiré

Fringe Projection Methods



$$\Phi_D = \Phi_C^r$$

$$\Phi_A^r \leftarrow \Phi_D$$



Acquisition of a motor combustion chamber by fringe (stripe) projection; analysis of the three-dimensional dataset (measuring area 100 x 100 mm)

If I subtract two phase map on the object and on the phase plane I get this:

$$\Delta\Phi_{DA} = \Phi_D - \Phi_A^r = \Phi_C^r - \Phi_A^r = \Delta\Phi_{AC}^r$$

▲ PID ▲ CAD Similar Triangles

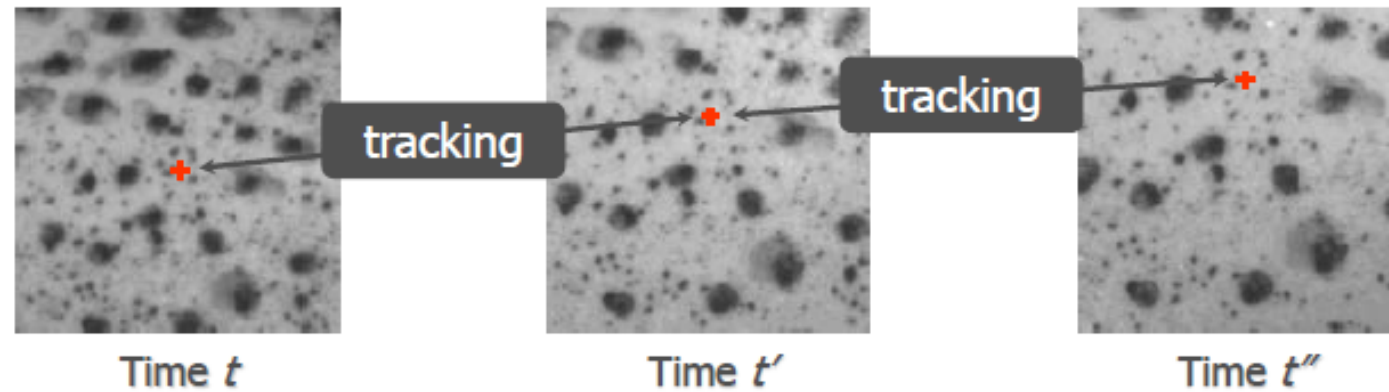
$$DB:AC = (l-z)/d \rightarrow zd = AC(l - ACz) \rightarrow z(d + AC) = AC l \rightarrow z = AC l / (d + AC)$$

$$z = AC l / d$$

$$z(x,y) \propto \Delta\Phi_{AC}^r = \Phi_D - \Phi_A^r$$

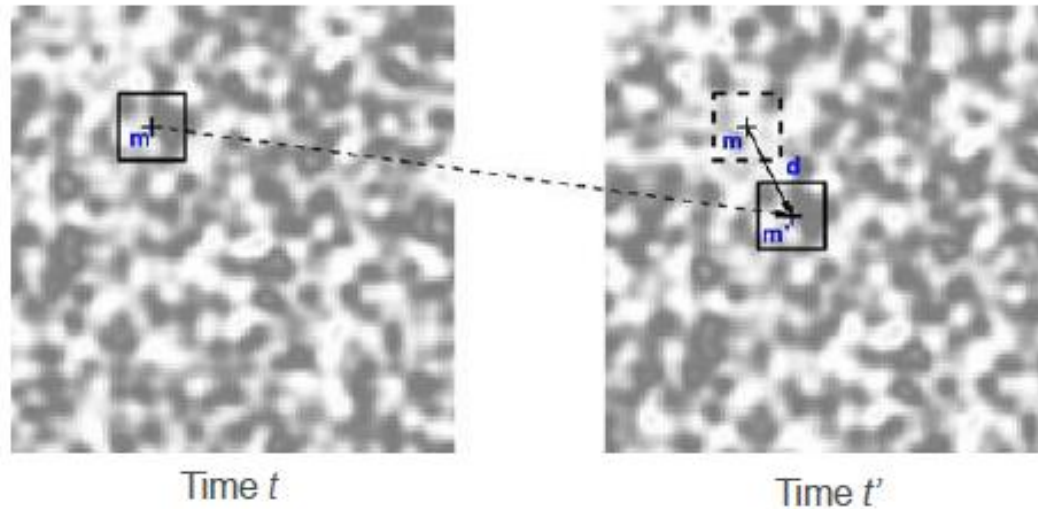
DIC

- How? Given a point and its signature in the undeformed image, **search/track** in deformed image for **the point** which has a **signature** which **maximizes a similarity function**



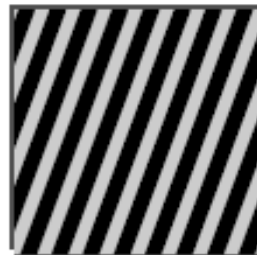
DIC

- **In practice**, a single value is not a unique signature of a point, hence **neighboring pixels are used**
- Such a collection of pixel values is called a **subset** or **window**



DIC

- The uniqueness of each signature is only guaranteed if the surface has a **non repetitive, isotropic, high contrast pattern**
- **Random textures** fulfill this constraint (speckle pattern)



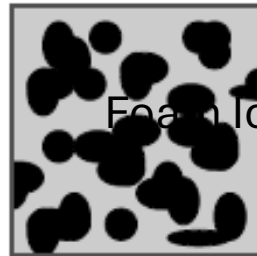
Repetitive
Anisotropic
High-contrast



Non-repetitive
Anisotropic
High-contrast



Non-repetitive
Isotropic
Low-contrast



Non-repetitive
Isotropic
High-contrast

Foam Iosipescu



Stress Concentration Airbus



Clear Aligners



Iosipescu FOAM

DIC

Image, in memory

100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100
0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0
100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100

Image, on screen

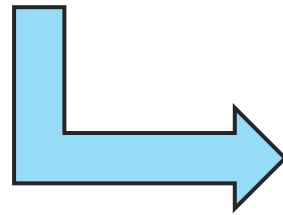
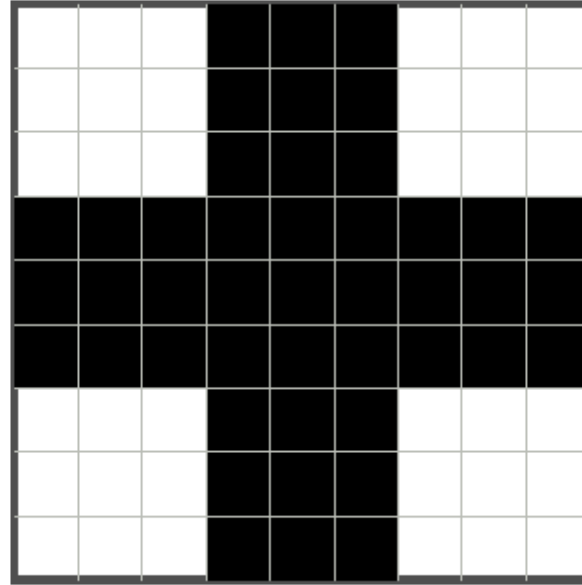
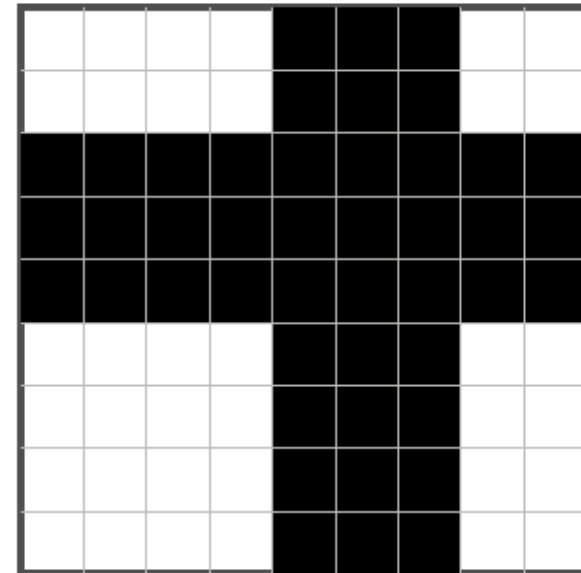


Image after motion, in memory

100	100	100	100	0	0	0	100	100
100	100	100	100	0	0	0	100	100
0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0
100	100	100	100	0	0	0	100	100
100	100	100	100	0	0	0	100	100
100	100	100	100	0	0	0	100	100
100	100	100	100	0	0	0	100	100

Image after motion, on screen

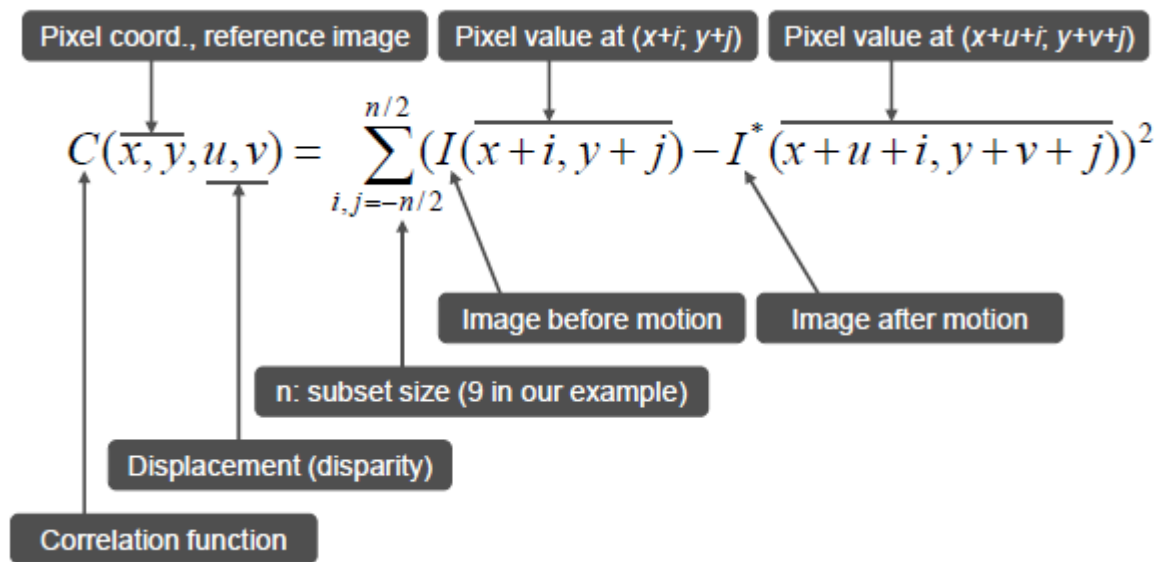


DIC

Image before motion									Image after motion								
100	100	100	0	0	0	100	100	100	100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100	100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100	0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
100	100	100	0	0	0	100	100	100	100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100	100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100	100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100	100	100	100	0	0	0	100	100	100

Subset

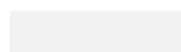
?



DIC

- Example: subset at $(x;y)=(5;5)$, displacement candidate $(u;v)=(-2;-2)$

$$C(5,5,-2,-2) = \sum_{i,j=-2}^2 (I(5+i,6+j) - I^*(5-2+i,5-2+j))^2$$



$$\begin{aligned} &(100-0)^2 + (0-0)^2 + (0-0)^2 + (0-0)^2 + (100-0)^2 + \\ &(0-100)^2 + (0-100)^2 + (0-100)^2 + (0-100)^2 + (0-0)^2 + \\ &(0-100)^2 + (0-100)^2 + (0-100)^2 + (0-100)^2 + (0-0)^2 + \\ &(0-100)^2 + (0-100)^2 + (0-100)^2 + (0-100)^2 + (0-0)^2 + \\ &(100-100)^2 + (0-100)^2 + (0-100)^2 + (0-100)^2 + (100-0)^2 = 18,000 \end{aligned}$$

100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100
0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0
100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100
100	100	100	0	0	0	100	100	100

$(x,y)=(5;5)$

Image before motion

100	100	100	100	0	0	0	100	100
100	100	100	100	0	0	0	100	100
0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	0	0
100	100	100	100	0	0	0	100	100
100	100	100	100	0	0	0	100	100
100	100	100	100	0	0	0	100	100
100	100	100	100	0	0	0	100	100

Image after motion

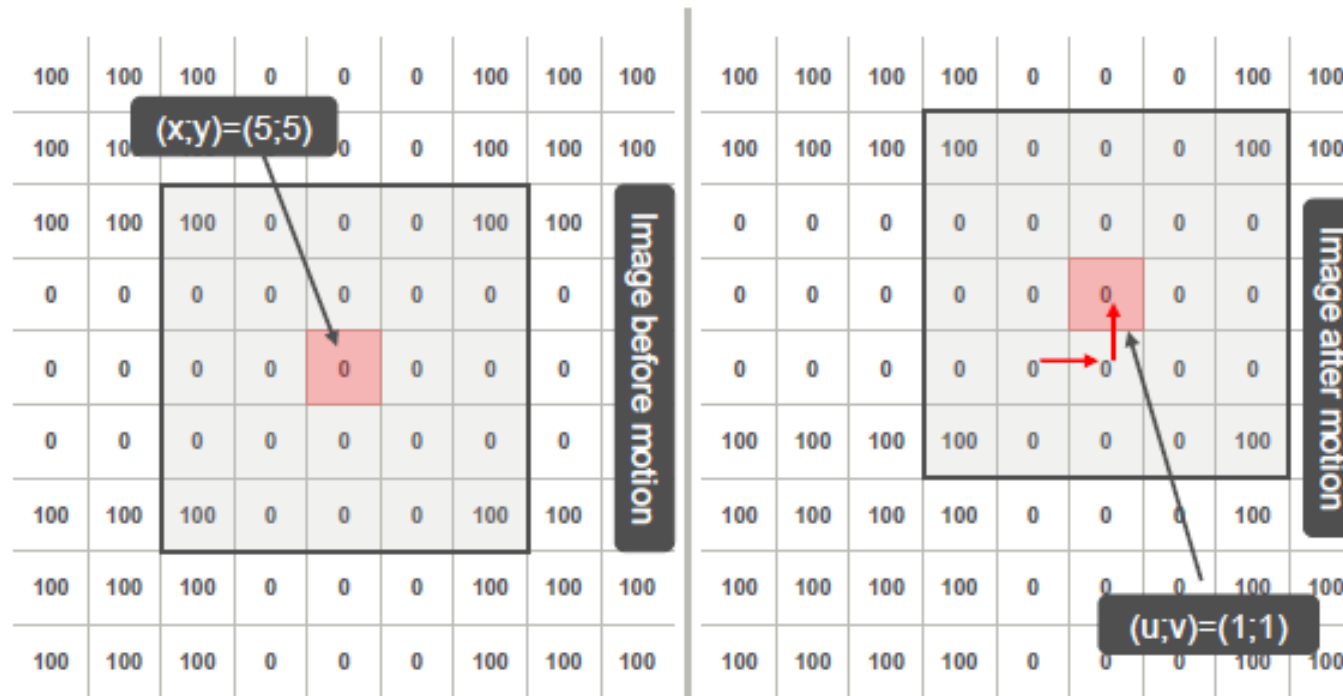
$(u,v)=(-2;-2)$

DIC

- Example: subset at $(x;y)=(5;5)$, displacement candidate $(u;v)=(1;1)$

$$C(5,5,1,1) = 0$$

- Better correlation score than candidate $(u;v)=(-2;-2)$ [18,000]
Indeed it is the smallest score achievable (perfect match)



$$C(5,5,1,1)=0$$

Perfect Match!

DIC

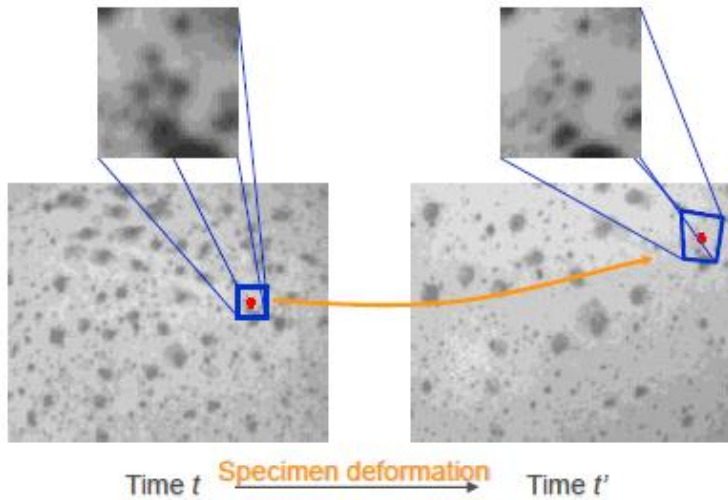
Image before motion									Image after motion								
103	101	99	2	0	1	105	100	96	99	100	101	102	3	0	2	100	102
101	104	98	1	4	3	101	98	100	101	97	98	101	1	2	0	96	102
103	96	99	0	2	2	102	103	98	0	1	3	3	2	0	1	2	0
2	3	0	1	1	2	3	0	1	1	0	3	0	2	1	1	0	3
1	3	3	0	2	1	0	3	0	1	3	2	0	1	1	2	2	0
0	0	2	0	3	0	2	0	0	101	100	100	103	0	2	1	102	101
98	101	102	0	1	0	96	97	102	97	99	100	101	3	2	0	97	101
97	98	103	0	2	0	103	98	100	101	103	98	101	0	1	1	99	96
102	99	101	2	0	0	104	102	101	102	99	96	103	2	3	3	102	100

$$C(5,5,1,1)=0$$

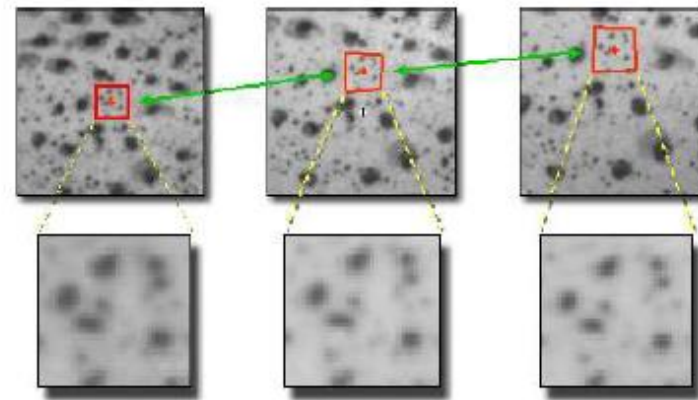
Best Match!

DIC

- General circumstances:
 - The subset in the deformed image has changed shape, e.g. a square initial subset is likely to be non-square

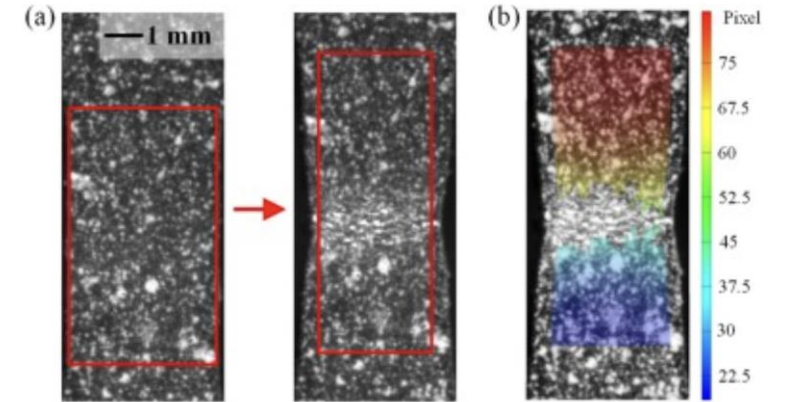


- Solution: model this displacement transformation (called **subset shape function**) and use it to define the deformed subset



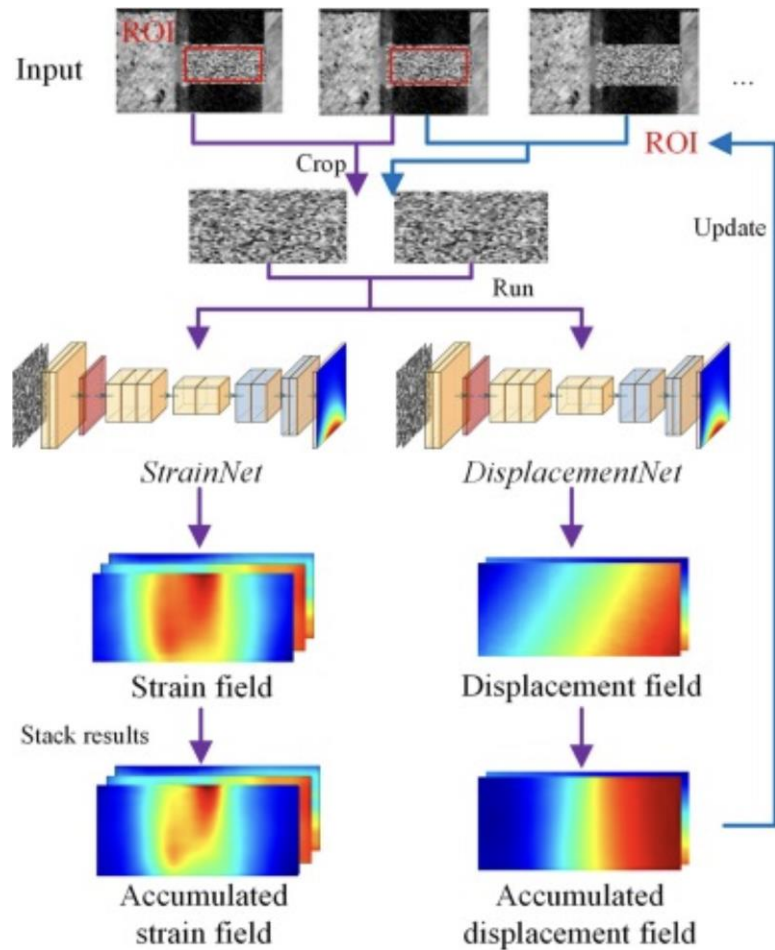
DIC current challenges and Machine Learning

- Improve Computational Time going toward real time evaluation
- Reduce error in calculating strain from displacement
- Manage with issue at high deformation up to paint breaking



Ru Yang, Yang Li, Danielle Zeng, Ping Guo, Deep DIC: Deep learning-based digital image correlation for end-to-end displacement and strain measurement. *Journal of Materials Processing Technology*, 302, 2022

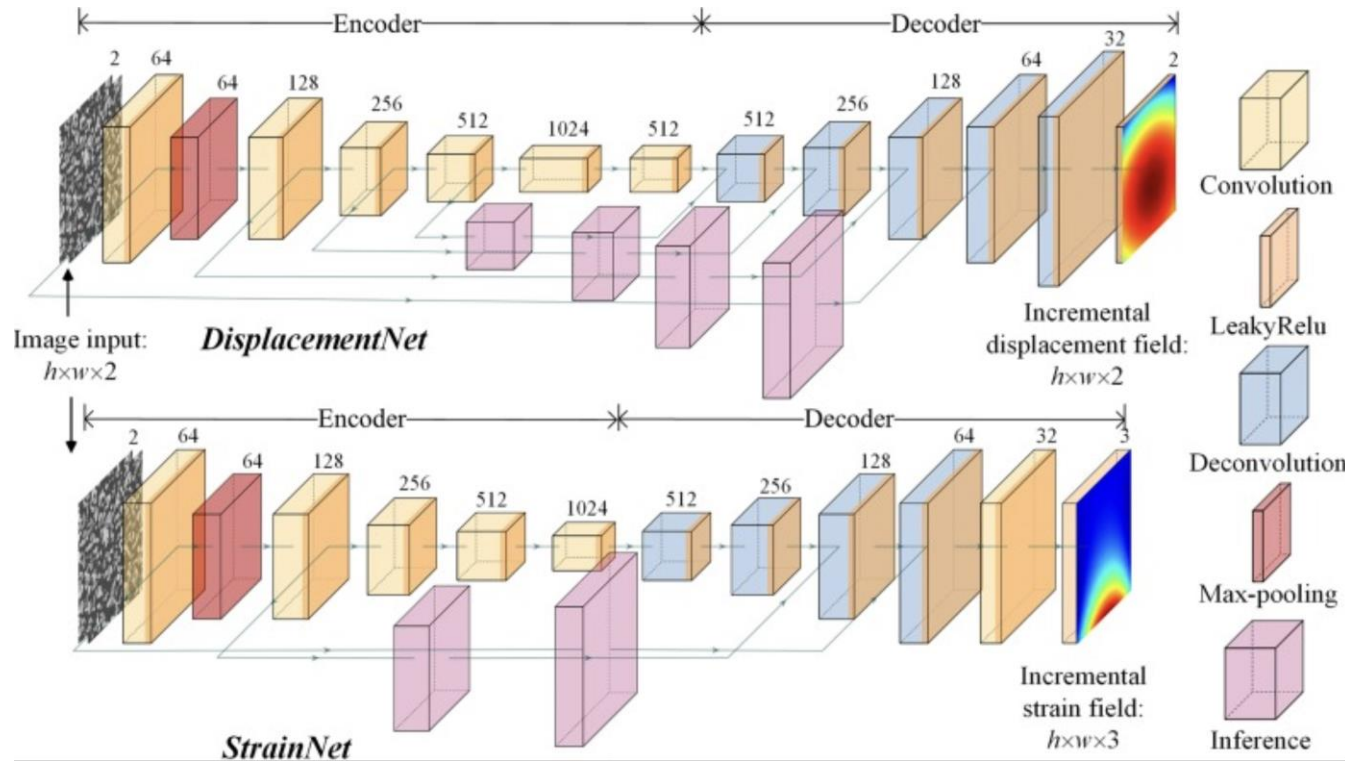
DIC current challenges and Machine Learning



Three ideas:

- Two separate net for Displacement and Strain
- Displacement and Strain Calculated in the incremental way
- Accumulated displacement is used to update the ROI

DIC current challenges and Machine Learning

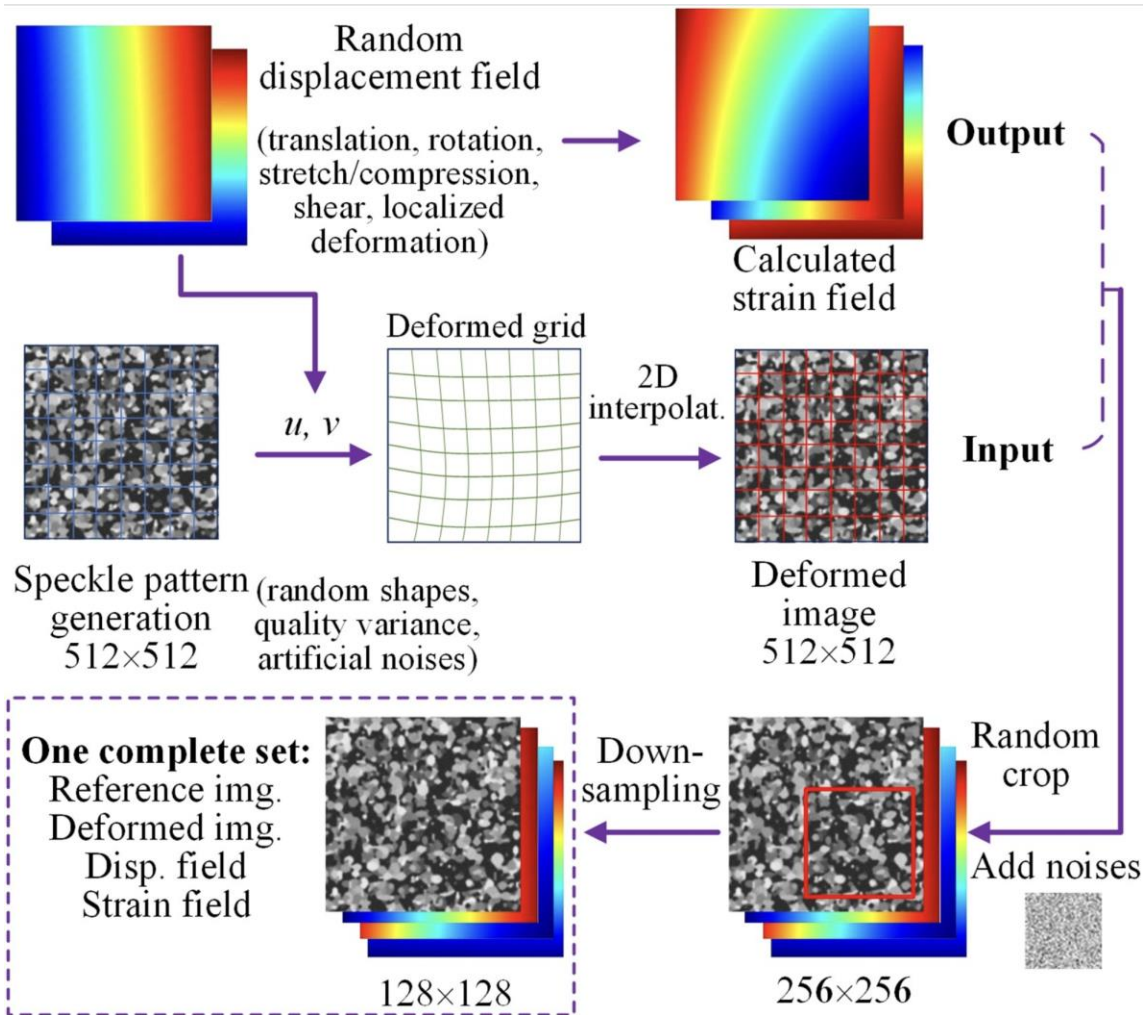


Using an encoder decoder architecture and Giving two input images (reference and calculation) you have:

Two displacement fields

Three strain fields

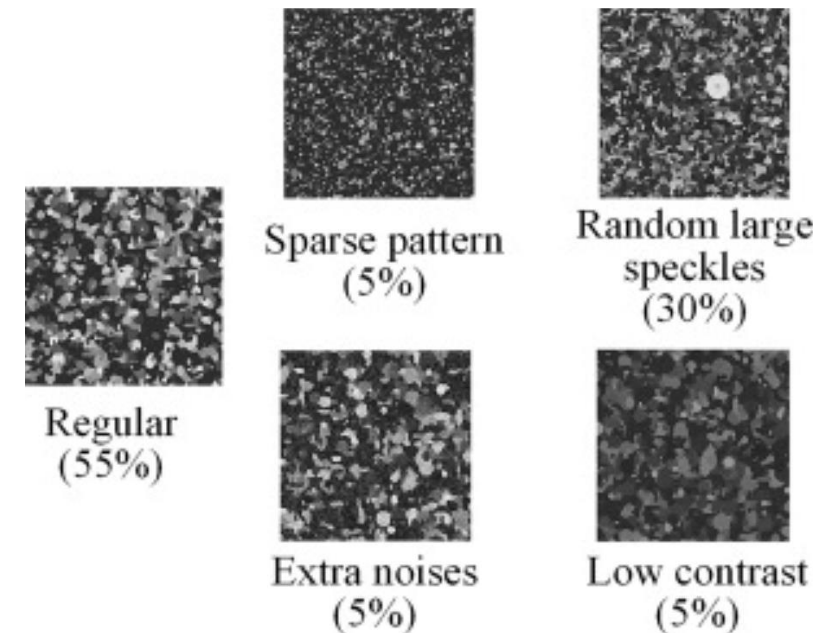
DIC current challenges and Machine Learning



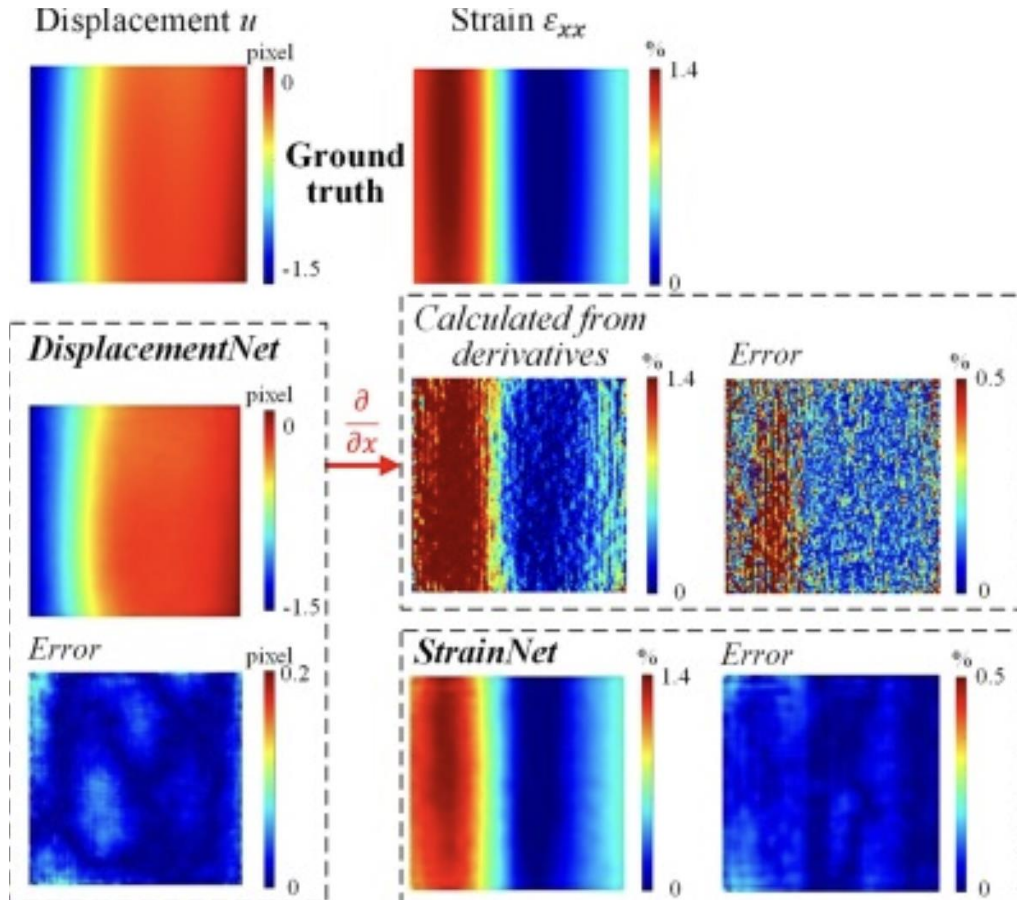
$$\begin{bmatrix} u \\ v \end{bmatrix} = \underbrace{\begin{bmatrix} \cos\theta & \sin\theta \\ -\sin\theta & \cos\theta \end{bmatrix}}_{\text{Rigidbodyrotation}} \cdot \underbrace{\begin{bmatrix} k_x - 1 & \gamma_x \\ \gamma_y & k_y - 1 \end{bmatrix}}_{\text{Uniformstretch andshear}} \cdot \begin{bmatrix} x \\ y \end{bmatrix} + \underbrace{\begin{bmatrix} u_x^g \\ u_y^g \end{bmatrix}}_{\text{2DGaussian deformation}}$$

$$+ \underbrace{\begin{bmatrix} t_x \\ t_y \end{bmatrix}}_{\text{Rigidbody translation}}$$

$$\begin{bmatrix} u_x^g \\ u_y^g \end{bmatrix} = \sum_{j=1}^N \begin{bmatrix} A_x^j e^{-\frac{1}{2} \left(\frac{x-x_0^j}{\sigma_{x0}^j} \right)^2 - \frac{1}{2} \left(\frac{y-y_0^j}{\sigma_{y0}^j} \right)^2} \\ A_y^j e^{-\frac{1}{2} \left(\frac{y-y_1^j}{\sigma_{y1}^j} \right)^2 - \frac{1}{2} \left(\frac{x-x_1^j}{\sigma_{x1}^j} \right)^2} \end{bmatrix}, N = 1 \text{ or } 2$$



DIC current challenges and Machine Learning



Calculated Strain Error

Max: 5.93%

Avg: 0.24 %

Strainnet Error

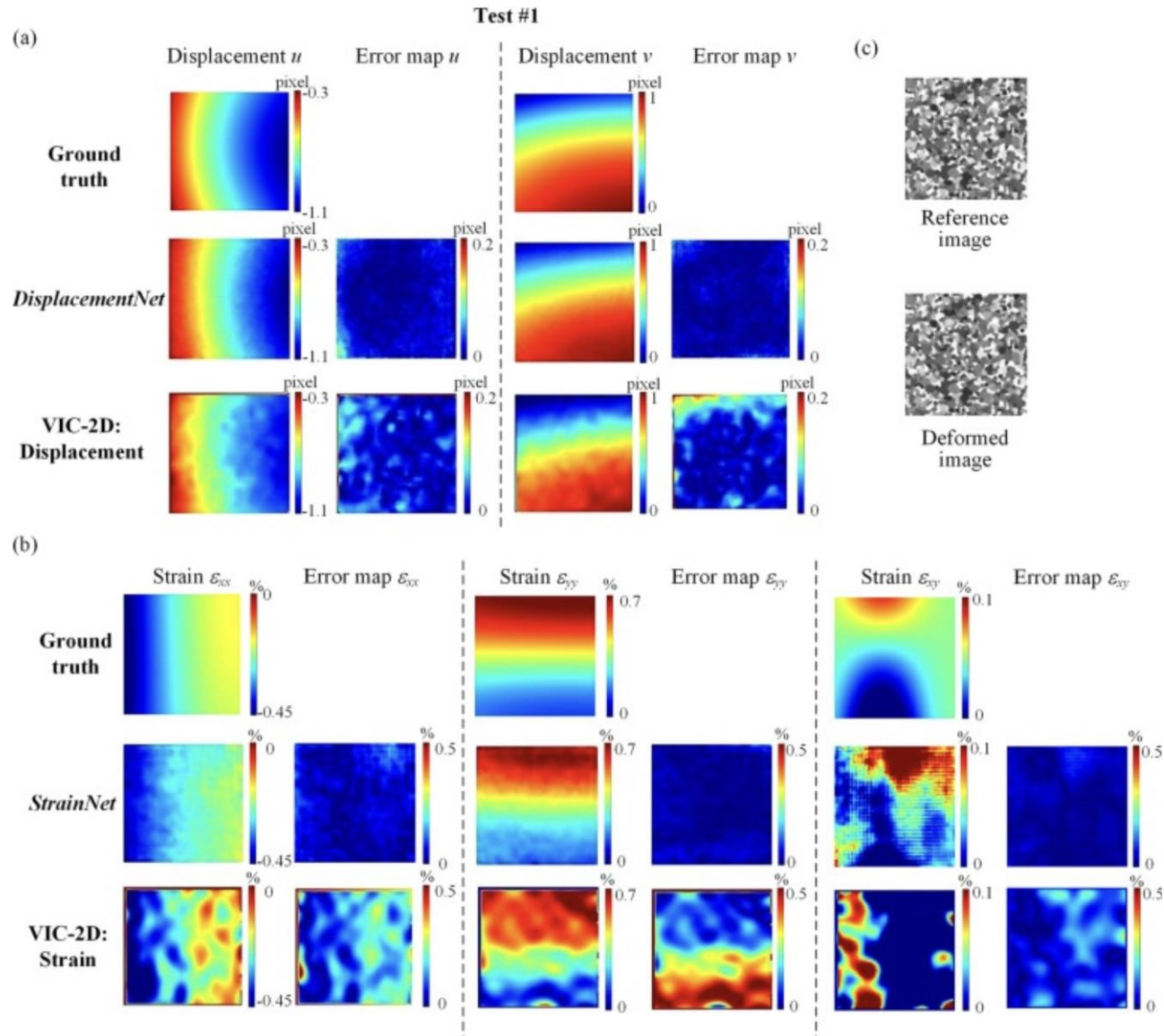
Max: 0.11 %

Avg: 0.018 %

Error in Strain Determination is reduced

But still not proved to manage large deformation at once

DIC current challenges and Machine Learning

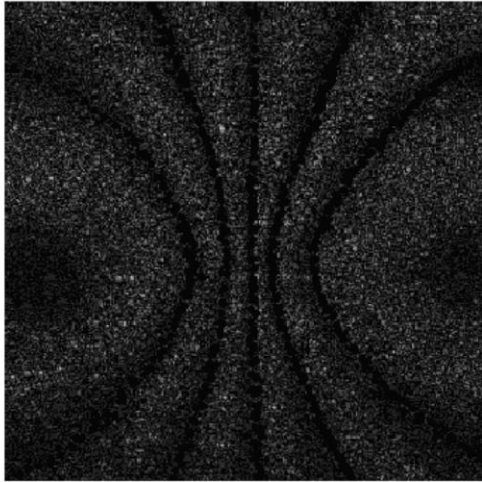


Higher accuracy both on displacement and Strain with respect to VIC-2D software

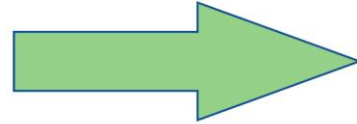
Other comparison can be done in terms of Calculation time
When applied to a sequence of 189 images
The net time for VIC 2D software was 27 s

Time for Deepnet was 2.35 s

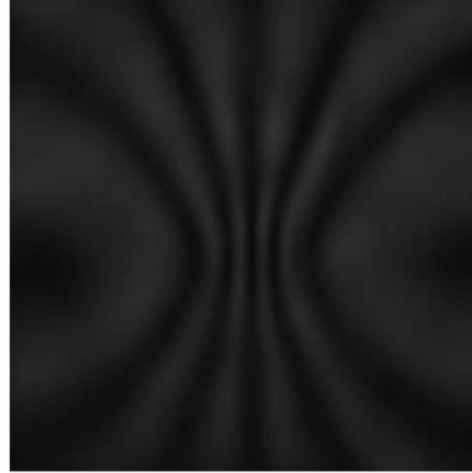
ESPI current challenges and Machine Learning



ESPI fringe pattern



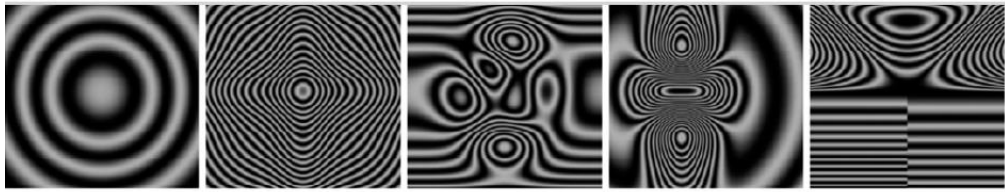
Filtering



ESPI fringe pattern
after filtering

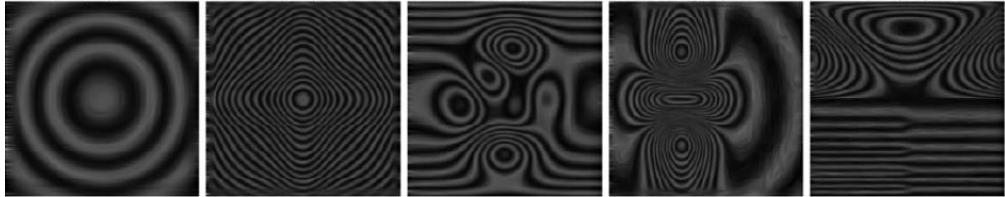
- Denoising is a process which is slowing the measurement chain
- When dealing with complex fringe pattern Global optimum denoising can hide some Local features
- Poor generalization

Wenbo Jiang, Tong Ren, Qianhua Fu Zeng, Deep Learning in the Phase Extraction of Electronic Speckle Pattern Interferometry. Electronics, 13(2), 2024



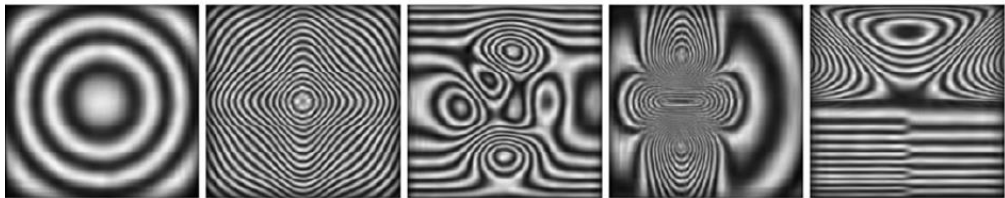
(a0) (b0) (c0) (d0) (e0)

Ground Truth



(a1) (b1) (c1) (d1) (e1)

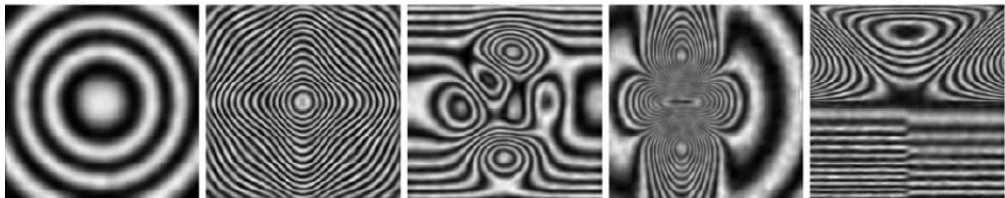
SOOPDE



(a2) (b2) (c2) (d2) (e2)

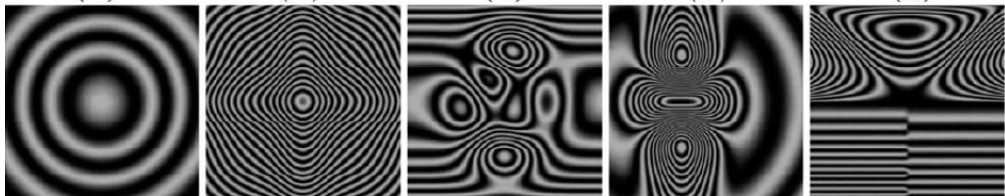
WFF

- Higher Contrast
- Higher Denoising
- Better shape Preservation



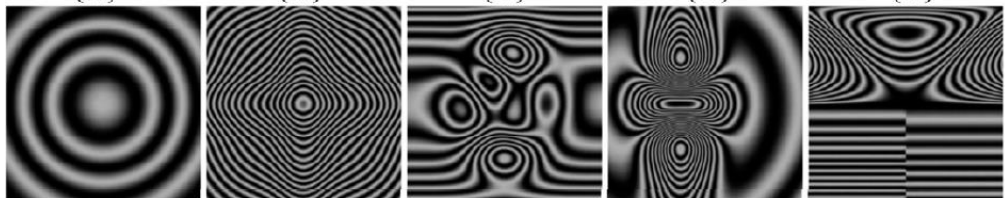
(a3) (b3) (c3) (d3) (e3)

BL Hilbert L2



(a4) (b4) (c4) (d4) (e4)

FDD NET



(a5) (b5) (c5) (d5) (e5)

MDD NET

Xu, M.; Tang, C.; Hong, N.; Lei, Z. MDD-Net: A generalized network for speckle removal with structure protection and shape preservation for various kinds of ESPI fringe patterns. Opt. Lasers Eng. 2022, 154, 107017.



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Thank You For Your Attention!



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